

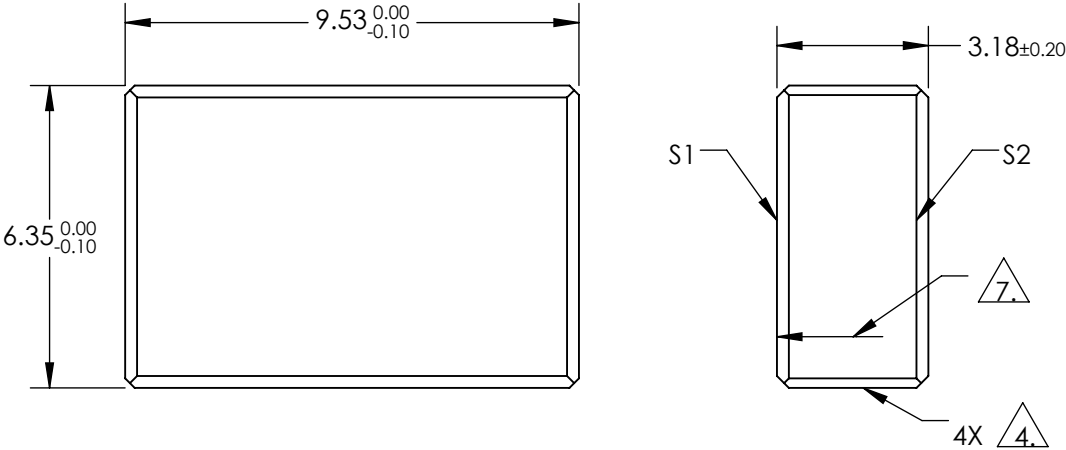
NOTES:

1. SUBSTRATE:  
Fused Silica
2. SURFACE S1 TO BE PARALLEL TO SURFACE S2 TO WITHIN <3 ARCMINS
3. COATING (APPLY ACROSS COATING APERTURE)

S1: R(ABS) >99.8% @ 532nm  
R(ABS) >99.5% @ 523 - 537nm  
DAMAGE THRESHOLD,  
PULSED: 15 J/cm<sup>2</sup> @ 532nm, 20ns, 20Hz  
CW: 1 MW/cm<sup>2</sup> @ 532nm

S2: NONE

4. FINE GROUND SURFACE
5. CLEAR APERTURE AND COATING APERTURE ARE CENTERED ON SURFACE
6. POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATIONS APPLY ACROSS CLEAR APERTURE
7. ARROW ON EDGE WITH LASER ETCH, PENCIL, OR PERMANENT INK POINTS TOWARDS SURFACE S1



**FOR INFORMATION ONLY:  
DO NOT MANUFACTURE  
PARTS TO THIS DRAWING**

SPECIFICATIONS SUBJECT TO CHANGE WITHOUT NOTICE  
DIMENSIONS ARE FOR REFERENCE ONLY

	S1	S2				
SHAPE	PLANO	PLANO	<div><div>THIRD ANGLE PROJECTION</div><div></div><div>ALL DIMS IN    mm</div></div> <div><div>Edmund Optics®</div><div>6.35 x 9.53mm 532nm 45°, Nd:YAG Laser Line Mirror</div></div>			
SURFACE QUALITY	10-5	COMMERCIAL POLISH				
SURFACE FLATNESS	0.10 WAVE	N/A				
MIN CLEAR APERTURE	5.40 x 8.10	N/A				
MIN COATING APERTURE	5.40 x 8.10	N/A				
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED	DWG NO	39640	SHEET 1 OF 1	